# imall

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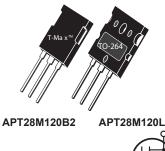


### **N-Channel MOSFET**

Power MOS 8<sup>TM</sup> is a high speed, high voltage N-channel switch-mode power MOSFET. A proprietary planar stripe design yields excellent reliability and manufacturability. Low switching loss is achieved with low input capacitance and ultra low  $C_{rss}$  "Miller" capacitance. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control slew rates during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency. Reliability in flyback, boost, forward, and other circuits is enhanced by the high avalanche energy capability.



1200V, 29A, 0.53Ω Max



Single die MOSFET



#### **FEATURES**

- Fast switching with low EMI/RFI
- Low R<sub>DS(on)</sub>
- Ultra low C<sub>rss</sub> for improved noise immunity
- Low gate charge
- Avalanche energy rated
- RoHS compliant

#### **TYPICAL APPLICATIONS**

- PFC and other boost converter
- Buck converter
- Two switch forward (asymmetrical bridge)
- Single switch forward
- Flyback
- Inverters

#### **Absolute Maximum Ratings**

Symbol	Parameter	Ratings	Unit
	Continuous Drain Current @ T <sub>C</sub> = 25°C	29	
D	Continuous Drain Current @ T <sub>C</sub> = 100°C	18	A
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	104	
V <sub>GS</sub>	Gate-Source Voltage	±30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>©</sup>	2165	mJ
I <sub>AR</sub>	Avalanche Current, Repetitive or Non-Repetitive	14	A

#### **Thermal and Mechanical Characteristics**

Symbol	Characteristic	Min	Тур	Max	Unit	
P <sub>D</sub>	Total Power Dissipation @ $T_{C} = 25^{\circ}C$			1135	W	
R <sub>θJC</sub>	Junction to Case Thermal Resistance			0.11	0.11 °C/W	
R <sub>ecs</sub>	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11			
T_,T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55		150	- °C	
TL	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W <sub>T</sub>	Package Weight		0.22		οz	
			6.2		g	
Torque	Mounting Torque (TO-264 Package), 4-40 or M3 screw			10	in∙lbf	
				1.1	N∙m	

**Static Characteristics** 

#### T<sub>J</sub> = 25°C unless otherwise specified

APT28M120B2 L

Symbol	Parameter	Test Conditions		Min	Тур	Мах	Unit
V <sub>BR(DSS)</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA		1200			V
$\Delta V_{BR(DSS)} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, $I_D = 250\mu A$			1.41		V/°C
R <sub>DS(on)</sub>	Drain-Source On Resistance <sup>③</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 14A			0.45	0.53	Ω
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 2.5 \text{mA}$		3	4	5	V
$\Delta V_{GS(th)} / \Delta T_J$	Threshold Voltage Temperature Coefficient				-10		mV/°C
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 1200V	T <sub>J</sub> = 25°C			100	
DSS		$V_{GS} = 0V$	T <sub>J</sub> = 125°C			500	μA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS} = \pm 30V$				±100	nA

#### **Dynamic Characteristics**

#### T<sub>J</sub> = 25°C unless otherwise specified

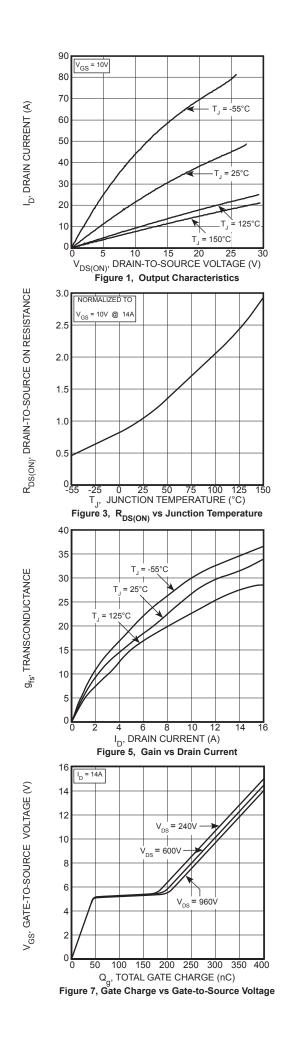
Symbol	Parameter	Test Conditions	Min	Тур	Мах	Unit	
9 <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> = 50V, I <sub>D</sub> = 14A		31		S	
C <sub>iss</sub>	Input Capacitance			9670			
C <sub>rss</sub>	Reverse Transfer Capacitance	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 25V f = 1MHz		115			
C <sub>oss</sub>	Output Capacitance			715			
C <sub>o(cr)</sub> ④	Effective Output Capacitance, Charge Related			275		pF	
C <sub>o(er)</sub> (5)	Effective Output Capacitance, Energy Related	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 800V$		140			
Q <sub>g</sub>	Total Gate Charge			300			
Q <sub>gs</sub>	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 14A,$ $V_{DS} = 600V$		50		nC	
Q <sub>gd</sub>	Gate-Drain Charge	v <sub>DS</sub> - 600V		140			
t <sub>d(on)</sub>	Turn-On Delay Time	Resistive Switching		50			
t <sub>r</sub>	Current Rise Time	V <sub>DD</sub> = 800V, I <sub>D</sub> = 14A		31		ne	
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{G}^{}$ = 2.20 <sup>®</sup> , $V_{GG}^{}$ = 15V		170		ns	
t <sub>f</sub>	Current Fall Time			48			

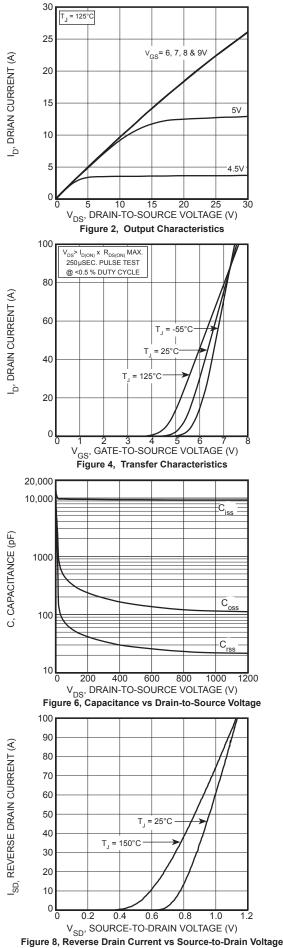
#### **Source-Drain Diode Characteristics**

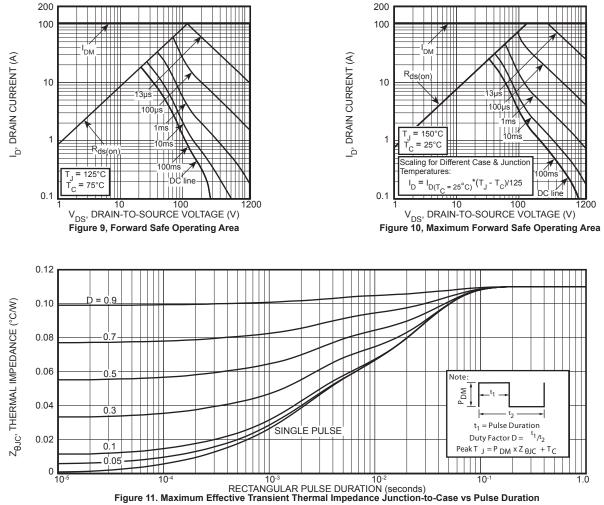
Symbol	Parameter	Test Conditions	Min	Тур	Мах	Unit
۱ <sub>s</sub>	Continuous Source Current (Body Diode)	MOSFET symbol showing the			29	A
I <sub>SM</sub>	Pulsed Source Current (Body Diode) <sup>①</sup>	integral reverse p-n junction diode (body diode)			104	
V <sub>SD</sub>	Diode Forward Voltage	$I_{SD} = 14A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> = 14A <sup>③</sup>		1290		ns
Q <sub>rr</sub>	Reverse Recovery Charge	di <sub>SD</sub> /dt = 100A/µs, T <sub>J</sub> = 25°C		33		μC
dv/dt	Peak Recovery dv/dt	$I_{SD}$ ≤ 14A, di/dt ≤1000A/µs, $V_{DD}$ = 100V, $T_J$ = 125°C			10	V/ns

- (1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- (2) Starting at  $T_J = 25^{\circ}$ C, L = 22.09mH,  $R_G = 2.2\Omega$ ,  $I_{AS} = 14A$ .
- (3) Pulse test: Pulse Width <  $380\mu$ s, duty cycle < 2%.
- (4) C<sub>o(cr)</sub> is defined as a fixed capacitance with the same stored charge as C<sub>OSS</sub> with V<sub>DS</sub> = 67% of V<sub>(BR)DSS</sub>.
  (5) C<sub>o(er)</sub> is defined as a fixed capacitance with the same stored energy as C<sub>OSS</sub> with V<sub>DS</sub> = 67% of V<sub>(BR)DSS</sub>. To calculate C<sub>o(er)</sub> for any value of V<sub>DS</sub> less than V<sub>(BR)DSS</sub>, use this equation: C<sub>o(er)</sub> = -4.40E-7/V<sub>DS</sub><sup>2</sup> + 5.34E-8/V<sub>DS</sub> + 7.59E-11.
- 6 R<sub>G</sub> is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.







T-MAX<sup>®</sup> (B2) Package Outline





